Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/693,640	FINK ET AL.
Examiner	Art Unit
Quynh H. Nguyen	2642

	SEAR	CHED	
Class	Subclass	Date	Examiner
379	93.17 93.23 265.01 265.02 265.03	6/15/2005	QN
379	265.11 309	6/15/2005	QN
above updated		12/19/05	QN

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
379	265.01 265.02 265.03 265.11 309	12/19/05	QN	

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
searched: east	6/15/2005	QN
inventor searched through PALM database	6/15/2005	QN
Consulted with Benny Tieu and Hector Agdeppa	12/14/05	QN
Interference search history print out	12/19/05	QИ
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